



Applications of Terahertz Sensing and Imaging

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Deadline for manuscript
submissions:

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Message from the Guest Editors

Sensing and imaging technologies in the terahertz-wave region (0.1-10 THz) offer potential in a vast number of applications, including gas sensing, spectroscopy, material characterization, hydration monitoring, manufacturing process control, non-destructive testing, biomedical and biomolecular sensing and imaging, security, and other applications. Submissions are invited that address recent advances in terahertz (THz) sensing and imaging for practical applications, THz spectroscopy, measurement methods for sensing and imaging in the THz frequency range, novel THz photonic, electronic, and plasmonic devices, THz device and materials physics, simulation methods relevant to the THz regime, THz signal processing, and other related research. Both original research and review articles are invited.





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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